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Surface chemical analysis — Auger electron spectroscopy and X-ray photoelectron spectroscopy — Methods used to determine peak intensities and information required when reporting results

Analyse chimique des surfaces — Spectroscopie des électrons Auger et spectroscopie de photoélectrons par rayons X — Méthodes utilisées pour la détermination de l'intensité des pics et informations requises pour l'expression des résultats



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Contents	Page
Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Symbols and abbreviated terms	1
5 Methods for peak-intensity determination — Direct spectrum	1
5.1 General	1
5.2 Selection and subtraction of an inelastic background	3
5.3 Measurement of peak intensity	3
5.4 Measurement of a peak intensity with computer software	4
5.5 Measurement of peak intensities for a spectrum with overlapping peaks	5
5.6 Uncertainty in measurement of peak area	5
6 Methods for peak intensity determination — Auger-electron differential spectrum	6
6.1 General	6
6.2 Measurement of Auger-electron differential intensity	6
6.3 Uncertainties in measurement of Auger-electron differential intensity	7
7 Reporting of methods used to measure peak intensities	8
7.1 General requirements	8
7.2 Methods used to determine peak intensities in direct spectra	8
7.3 Methods used to obtain and determine peak intensities in Auger-electron differential spectra ..	9
Annex A (informative) Instrumental effects on measured intensities	10
Annex B (informative) Useful integration limits for determination of peak intensities in XPS spectra	11
Bibliography	13

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 20903 was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 5, *Auger electron spectroscopy*.

This second edition cancels and replaces the first edition (ISO 20903:2006), which has been revised to include an additional annex (Annex B) giving advice on the selection of the limits between which the peak intensity is measured in X-ray photoelectron spectroscopy.

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Introduction

An important feature of Auger electron spectroscopy (AES) and X-ray photoelectron spectroscopy (XPS) is the ability to obtain a quantitative analysis of the surface region of a solid sample. Such an analysis requires the determination of the intensities of spectral components.

There are several methods of peak-intensity measurement that are applicable to AES and XPS. In practice, the choice of method will depend upon the type of sample being analysed, the capabilities of the instrumentation used, and the methods of data acquisition and treatment available.

This International Standard is expected to have two main areas of application. First, it provides a description of methods that may be used in the determination of the intensity of a peak for an element in a given spectrum. Information is given on the origin of uncertainties in the processes involved, and on how these uncertainties may be reduced. Second, this International Standard specifies reporting requirements for the methods used for peak-intensity measurements so that other analysts may use published results with confidence.